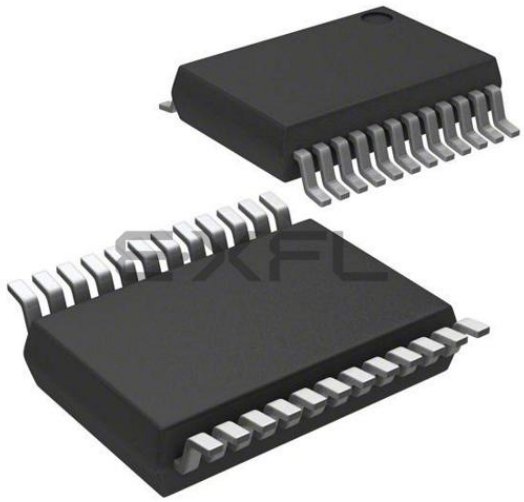

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What is "Embedded - Microcontrollers"?

"Embedded - Microcontrollers" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

Applications of "Embedded - Microcontrollers"

Details	
Product Status	Active
Core Processor	CIP-51 8051
Core Size	8-Bit
Speed	50MHz
Connectivity	I²C, SMBus, SPI, UART/USART
Peripherals	Brown-out Detect/Reset, POR, PWM, WDT
Number of I/O	21
Program Memory Size	16KB (16K x 8)
Program Memory Type	FLASH
EEPROM Size	-
RAM Size	2.25K x 8
Voltage - Supply (Vcc/Vdd)	2.2V ~ 3.6V
Data Converters	A/D 20x12b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 125°C (TA)
Mounting Type	Surface Mount
Package / Case	24-SSOP (0.154", 3.90mm Width)
Supplier Device Package	24-QSOP
Purchase URL	https://www.e-xfl.com/product-detail/silicon-labs/efm8bb21f16i-c-qsop24

2. Ordering Information

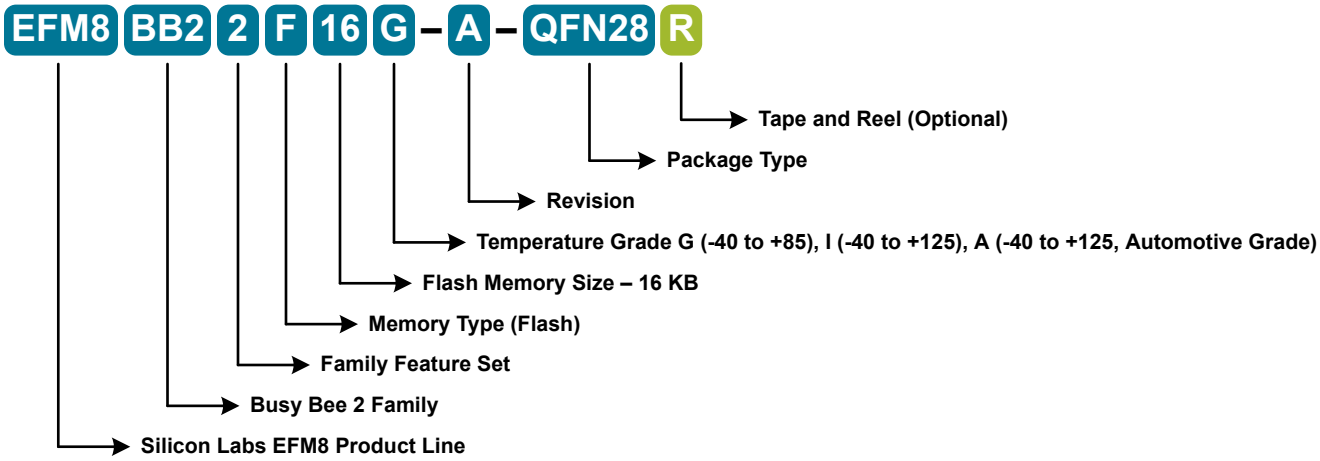

Figure 2.1. EFM8BB2 Part Numbering

All EFM8B2 family members have the following features:

- CIP-51 Core running up to 50 MHz
- Three Internal Oscillators (49 MHz, 24.5 MHz and 80 kHz)
- SMBus
- I2C Slave
- SPI
- 2 UARTs
- 3-Channel Programmable Counter Array (PWM, Clock Generation, Capture/Compare)
- 5 16-bit Timers
- 2 Analog Comparators
- 12-bit Analog-to-Digital Converter with integrated multiplexer, voltage reference, and temperature sensor
- 16-bit CRC Unit
- AEC-Q100 qualified
- Pre-loaded UART bootloader

In addition to these features, each part number in the EFM8BB2 family has a set of features that vary across the product line. The product selection guide shows the features available on each family member.

Table 2.1. Product Selection Guide

Ordering Part Number	Flash Memory (KB)	RAM (Bytes)	Digital Port I/Os (Total)	ADC0 Channels	Comparator 0 Inputs	Comparator 1 Inputs	Pb-free (RoHS Compliant)	5-to-3.3 V Regulator	Temperature Range	Package
EFM8BB22F16G-C-QFN28	16	2304	22	20	10	12	Yes	Yes	-40 to +85 ºC	QFN28
EFM8BB21F16G-C-QSOP24	16	2304	21	20	10	12	Yes	—	-40 to +85 ºC	QSOP24
EFM8BB21F16G-C-QFN20	16	2304	16	15	10	7	Yes	—	-40 to +85 ºC	QFN20
EFM8BB22F16I-C-QFN28	16	2304	22	20	10	12	Yes	Yes	-40 to +125 ºC	QFN28
EFM8BB21F16I-C-QSOP24	16	2304	21	20	10	12	Yes	—	-40 to +125 ºC	QSOP24

Ordering Part Number	Flash Memory (KB)	RAM (Bytes)	Digital Port I/Os (Total)	ADC0 Channels	Comparator 0 Inputs	Comparator 1 Inputs	Pb-free (RoHS Compliant)	5-to-3.3 V Regulator	Temperature Range	Package
EFM8BB21F16I-C-QFN20	16	2304	16	15	10	7	Yes	—	-40 to +125 ºC	QFN20
EFM8BB22F16A-C-QFN28	16	2304	22	20	10	12	Yes	Yes	-40 to +125 ºC	QFN28
EFM8BB21F16A-C-QFN20	16	2304	16	15	10	7	Yes	—	-40 to +125 ºC	QFN20

The A-grade (i.e. EFM8BB21F16A-C-QFN20) devices receive full automotive quality production status, including AEC-Q100 qualification, registration with International Material Data System (IMDS), and Part Production Approval Process (PPAP) documentation. PPAP documentation is available at www.silabs.com with a registered and NDA approved user account.

I2C Slave (I2CSLAVE0)

The I2C Slave interface is a 2-wire, bidirectional serial bus that is compatible with the I2C Bus Specification 3.0. It is capable of transferring in high-speed mode (HS-mode) at speeds of up to 3.4 Mbps. Firmware can write to the I2C interface, and the I2C interface can autonomously control the serial transfer of data. The interface also supports clock stretching for cases where the core may be temporarily prohibited from transmitting a byte or processing a received byte during an I2C transaction. This module operates only as an I2C slave device.

The I2C module includes the following features:

- Standard (up to 100 kbps), Fast (400 kbps), Fast Plus (1 Mbps), and High-speed (3.4 Mbps) transfer speeds
- Support for slave mode only
- Clock low extending (clock stretching) to interface with faster masters
- Hardware support for 7-bit slave address recognition
- Transmit and receive FIFOs (two bytes) to help increase throughput in faster applications

16-bit CRC (CRC0)

The cyclic redundancy check (CRC) module performs a CRC using a 16-bit polynomial. CRC0 accepts a stream of 8-bit data and posts the 16-bit result to an internal register. In addition to using the CRC block for data manipulation, hardware can automatically CRC the flash contents of the device.

The CRC module is designed to provide hardware calculations for flash memory verification and communications protocols. The CRC module supports the standard CCITT-16 16-bit polynomial (0x1021), and includes the following features:

- Support for CCITT-16 polynomial
- Byte-level bit reversal
- Automatic CRC of flash contents on one or more 256-byte blocks
- Initial seed selection of 0x0000 or 0xFFFF

3.7 Analog

12-Bit Analog-to-Digital Converter (ADC0)

The ADC is a successive-approximation-register (SAR) ADC with 12-, 10-, and 8-bit modes, integrated track-and hold and a programmable window detector. The ADC is fully configurable under software control via several registers. The ADC may be configured to measure different signals using the analog multiplexer. The voltage reference for the ADC is selectable between internal and external reference sources.

- Up to 20 external inputs.
- Single-ended 12-bit and 10-bit modes.
- Supports an output update rate of 200 ksps samples per second in 12-bit mode or 800 ksps samples per second in 10-bit mode.
- Operation in low power modes at lower conversion speeds.
- Asynchronous hardware conversion trigger, selectable between software, external I/O and internal timer sources.
- Output data window comparator allows automatic range checking.
- Support for burst mode, which produces one set of accumulated data per conversion-start trigger with programmable power-on settling and tracking time.
- Conversion complete and window compare interrupts supported.
- Flexible output data formatting.
- Includes an internal fast-settling reference with two levels (1.65 V and 2.4 V) and support for external reference and signal ground.
- Integrated temperature sensor.

Low Current Comparators (CMP0, CMP1)

Analog comparators are used to compare the voltage of two analog inputs, with a digital output indicating which input voltage is higher. External input connections to device I/O pins and internal connections are available through separate multiplexers on the positive and negative inputs. Hysteresis, response time, and current consumption may be programmed to suit the specific needs of the application.

The comparator includes the following features:

- Up to 10 (CMP0) or 12 (CMP1) external positive inputs
- Up to 10 (CMP0) or 12 (CMP1) external negative inputs
- Additional input options:
  - Internal connection to LDO output
  - Direct connection to GND
  - Direct connection to VDD
  - Dedicated 6-bit reference DAC
- Synchronous and asynchronous outputs can be routed to pins via crossbar
- Programmable hysteresis between 0 and ±20 mV
- Programmable response time
- Interrupts generated on rising, falling, or both edges
- PWM output kill feature

3.8 Reset Sources

Reset circuitry allows the controller to be easily placed in a predefined default condition. On entry to this reset state, the following occur:

- The core halts program execution.
- Module registers are initialized to their defined reset values unless the bits reset only with a power-on reset.
- External port pins are forced to a known state.
- Interrupts and timers are disabled.

All registers are reset to the predefined values noted in the register descriptions unless the bits only reset with a power-on reset. The contents of RAM are unaffected during a reset; any previously stored data is preserved as long as power is not lost. The Port I/O latches are reset to 1 in open-drain mode. Weak pullups are enabled during and after the reset. For Supply Monitor and power-on resets, the RSTb pin is driven low until the device exits the reset state. On exit from the reset state, the program counter (PC) is reset, and the system clock defaults to an internal oscillator. The Watchdog Timer is enabled, and program execution begins at location 0x0000.

Reset sources on the device include the following:

- Power-on reset
- External reset pin
- Comparator reset
- Software-triggered reset
- Supply monitor reset (monitors VDD supply)
- Watchdog timer reset
- Missing clock detector reset
- Flash error reset

3.9 Debugging

The EFM8BB2 devices include an on-chip Silicon Labs 2-Wire (C2) debug interface to allow flash programming and in-system debugging with the production part installed in the end application. The C2 interface uses a clock signal (C2CK) and a bi-directional C2 data signal (C2D) to transfer information between the device and a host system. See the C2 Interface Specification for details on the C2 protocol.

4.1.2 Power Consumption

Table 4.2. Power Consumption

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Digital Core Supply Current (G-grade devices, -40 °C to +85 °C)						
Normal Mode-Full speed with code executing from flash	I_{DD}	F_{SYSCLK} = 49 MHz (HFOSC1)[2]	—	9.4	10.1	mA
		F_{SYSCLK} = 24.5 MHz (HFOSC0)[2]	—	4.5	5.2	mA
		F_{SYSCLK} = 1.53 MHz (HFOSC0)[2]	—	600	900	µA
		F_{SYSCLK} = 80 kHz[3]	—	145	410	µA
Idle Mode-Core halted with peripherals running	I_{DD}	F_{SYSCLK} = 49 MHz (HFOSC1)[2]	—	6.3	6.8	mA
		F_{SYSCLK} = 24.5 MHz (HFOSC0)[2]	—	2.9	3.3	mA
		F_{SYSCLK} = 1.53 MHz (HFOSC0)[2]	—	440	750	µA
		F_{SYSCLK} = 80 kHz[3]	—	130	420	µA
Suspend Mode-Core halted and high frequency clocks stopped, Supply monitor off.	I_{DD}	LFO Running	—	125	400	µA
		LFO Stopped	—	120	390	µA
Snooze Mode-Core halted and high frequency clocks stopped. Regulator in low-power state, Supply monitor off.	I_{DD}	LFO Running	—	25	300	µA
		LFO Stopped	—	20	290	µA
Stop Mode—Core halted and all clocks stopped,Internal LDO On, Supply monitor off.	I_{DD}		—	120	390	µA
Shutdown Mode—Core halted and all clocks stopped,Internal LDO Off, Supply monitor off.	I_{DD}		—	0.2	3	µA
Digital Core Supply Current (I-grade or A-grade devices, -40 °C to +125 °C)						
Normal Mode-Full speed with code executing from flash	I_{DD}	F_{SYSCLK} = 49 MHz (HFOSC1)[2]	—	9.4	10.9	mA
		F_{SYSCLK} = 24.5 MHz (HFOSC0)[2]	—	4.5	5.6	mA
		F_{SYSCLK} = 1.53 MHz (HFOSC0)[2]	—	600	1555	µA
		F_{SYSCLK} = 80 kHz[3]	—	145	1070	µA
Idle Mode-Core halted with peripherals running	I_{DD}	F_{SYSCLK} = 49 MHz (HFOSC1)[2]	—	6.3	7.4	mA
		F_{SYSCLK} = 24.5 MHz (HFOSC0)[2]	—	2.9	3.9	mA
		F_{SYSCLK} = 1.53 MHz (HFOSC0)[2]	—	440	1400	µA
		F_{SYSCLK} = 80 kHz[3]	—	130	1050	µA
Suspend Mode-Core halted and high frequency clocks stopped, Supply monitor off.	I_{DD}	LFO Running	—	125	1050	µA
		LFO Stopped	—	120	1045	µA
Snooze Mode-Core halted and high frequency clocks stopped. Regulator in low-power state, Supply monitor off.	I_{DD}	LFO Running	—	25	950	µA
		LFO Stopped	—	20	940	µA

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Stop Mode—Core halted and all clocks stopped,Internal LDO On, Supply monitor off.	I_{DD}		—	120	1045	µA
Shutdown Mode—Core halted and all clocks stopped,Internal LDO Off, Supply monitor off.	I_{DD}		—	0.2	15	µA
Analog Peripheral Supply Currents (-40 °C to +125 °C)						
High-Frequency Oscillator 0	I_{HFOSC0}	Operating at 24.5 MHz, T_A = 25 °C	—	105	—	µA
High-Frequency Oscillator 1	I_{HFOSC1}	Operating at 49 MHz, T_A = 25 °C	—	865	940	µA
Low-Frequency Oscillator	I_{LFOSC}	Operating at 80 kHz, T_A = 25 °C	—	4	—	µA
ADC0 Always-on[4]	I_{ADC}	800 ksps, 10-bit conversions or 200 ksps, 12-bit conversions Normal bias settings V_{DD} = 3.0 V	—	820	1200	µA
		250 ksps, 10-bit conversions or 62.5 ksps 12-bit conversions Low power bias settings V_{DD} = 3.0 V	—	405	580	µA
ADC0 Burst Mode, 10-bit single conversions, external reference	I_{ADC}	200 ksps, V_{DD} = 3.0 V	—	370	—	µA
		100 ksps, V_{DD} = 3.0 V	—	185	—	µA
		10 ksps, V_{DD} = 3.0 V	—	20	—	µA
ADC0 Burst Mode, 10-bit single conversions, internal reference, Low power bias settings	I_{ADC}	200 ksps, V_{DD} = 3.0 V	—	485	—	µA
		100 ksps, V_{DD} = 3.0 V	—	245	—	µA
		10 ksps, V_{DD} = 3.0 V	—	25	—	µA
ADC0 Burst Mode, 12-bit single conversions, external reference	I_{ADC}	100 ksps, V_{DD} = 3.0 V	—	505	—	µA
		50 ksps, V_{DD} = 3.0 V	—	255	—	µA
		10 ksps, V_{DD} = 3.0 V	—	50	—	µA
ADC0 Burst Mode, 12-bit single conversions, internal reference	I_{ADC}	100 ksps, V_{DD} = 3.0 V, Normal bias	—	950	—	µA
		50 ksps, V_{DD} = 3.0 V, Low power bias	—	415	—	µA
		10 ksps, V_{DD} = 3.0 V, Low power bias	—	80	—	µA
Internal ADC0 Reference, Always-on[5]	I_{VREFFS}	Normal Power Mode	—	680	790	µA
		Low Power Mode	—	160	210	µA

4.1.7 External Clock Input

Table 4.7. External Clock Input

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
External Input CMOS Clock Frequency (at EXTCLK pin)	f_{CMOS}		0	—	50	MHz
External Input CMOS Clock High Time	t_{CMOSH}		9	—	—	ns
External Input CMOS Clock Low Time	t_{CMOSL}		9	—	—	ns

4.1.8 ADC

Table 4.8. ADC

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Resolution	N_{bits}	12 Bit Mode		12		Bits
		10 Bit Mode		10		Bits
Throughput Rate (High Speed Mode)	f_S	12 Bit Mode	—	—	200	ksps
		10 Bit Mode	—	—	800	ksps
Throughput Rate (Low Power Mode)	f_S	12 Bit Mode	—	—	62.5	ksps
		10 Bit Mode	—	—	250	ksps
Tracking Time	t_{TRK}	High Speed Mode	230	—	—	ns
		Low Power Mode	450	—	—	ns
Power-On Time	t_{PWR}		1.2	—	—	µs
SAR Clock Frequency	f_{SAR}	High Speed Mode, Reference is 2.4 V internal	—	—	6.25	MHz
		High Speed Mode, Reference is not 2.4 V internal	—	—	12.5	MHz
		Low Power Mode	—	—	4	MHz
Conversion Time	t_{CNV}	10-Bit Conversion, SAR Clock = 12.25 MHz, System Clock = 24.5 MHz.		1.1		µs
Sample/Hold Capacitor	C_{SAR}	Gain = 1	—	5	—	pF
		Gain = 0.5	—	2.5	—	pF
Input Pin Capacitance	C_{IN}		—	20	—	pF
Input Mux Impedance	R_{MUX}		—	550	—	Ω
Voltage Reference Range	V_{REF}		1	—	V_{DD}	V
Input Voltage Range[1]	V_{IN}	Gain = 1	0	—	V_{REF}	V
		Gain = 0.5	0	—	$2xV_{REF}$	V
Power Supply Rejection Ratio	$PSRR_{ADC}$		—	70	—	dB
DC Performance						
Integral Nonlinearity	INL	12 Bit Mode	—	±1	±2.3	LSB
		10 Bit Mode	—	±0.2	±0.6	LSB
Differential Nonlinearity (Guaranteed Monotonic)	DNL	12 Bit Mode	-1	±0.7	1.9	LSB
		10 Bit Mode	—	±0.2	±0.6	LSB
Offset Error	E_{OFF}	12 Bit Mode, VREF = 1.65 V	-3	0	3	LSB
		10 Bit Mode, VREF = 1.65 V	-2	0	2	LSB
Offset Temperature Coefficient	TC_{OFF}		—	0.004	—	LSB/°C

4.1.13 Comparators

Table 4.13. Comparators

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Response Time, CPMD = 00 (Highest Speed)	t_{RESP0}	+100 mV Differential, V_{CM} = 1.65 V	—	110	—	ns
		-100 mV Differential, V_{CM} = 1.65 V	—	160	—	ns
Response Time, CPMD = 11 (Lowest Power)	t_{RESP3}	+100 mV Differential, V_{CM} = 1.65 V	—	1.2	—	µs
		-100 mV Differential, V_{CM} = 1.65 V	—	4.5	—	µs
Positive Hysteresis Mode 0 (CPMD = 00)	HYS_{CP+}	CPHYP = 00	—	0.4	—	mV
		CPHYP = 01	—	8	—	mV
		CPHYP = 10	—	16	—	mV
		CPHYP = 11	—	32	—	mV
Negative Hysteresis Mode 0 (CPMD = 00)	HYS_{CP-}	CPHYN = 00	—	-0.4	—	mV
		CPHYN = 01	—	-8	—	mV
		CPHYN = 10	—	-16	—	mV
		CPHYN = 11	—	-32	—	mV
Positive Hysteresis Mode 3 (CPMD = 11)	HYS_{CP+}	CPHYP = 00	—	1.5	—	mV
		CPHYP = 01	—	4	—	mV
		CPHYP = 10	—	8	—	mV
		CPHYP = 11	—	16	—	mV
Negative Hysteresis Mode 3 (CPMD = 11)	HYS_{CP-}	CPHYN = 00	—	-1.5	—	mV
		CPHYN = 01	—	-4	—	mV
		CPHYN = 10	—	-8	—	mV
		CPHYN = 11	—	-16	—	mV
Input Range (CP+ or CP-)	V_{IN}		-0.25	—	V_{DD}+0.25	V
Input Pin Capacitance	C_{CP}		—	7.5	—	pF
Internal Reference DAC Resolution	N_{bits}			6		bits
Common-Mode Rejection Ratio	$CMRR_{CP}$		—	70	—	dB
Power Supply Rejection Ratio	$PSRR_{CP}$		—	72	—	dB
Input Offset Voltage	V_{OFF}	T_A = 25 °C	-10	0	10	mV
Input Offset Tempco	TC_{OFF}		—	3.5	—	µV/°

4.3 Absolute Maximum Ratings

Stresses above those listed in Table 4.16 Absolute Maximum Ratings on page 24 may cause permanent damage to the device. This is a stress rating only and functional operation of the devices at those or any other conditions above those indicated in the operation listings of this specification is not implied. Exposure to maximum rating conditions for extended periods may affect device reliability. For more information on the available quality and reliability data, see the Quality and Reliability Monitor Report at http://www.silabs.com/support/quality/pages/default.aspx.

Table 4.16. Absolute Maximum Ratings

Parameter	Symbol	Test Condition	Min	Max	Unit
Ambient Temperature Under Bias	T_{BIAS}		-55	125	°C
Storage Temperature	T_{STG}		-65	150	°C
Voltage on VDD	V_{DD}		GND-0.3	4.2	V
Voltage on VREGIN	V_{REGIN}		GND-0.3	5.8	V
Voltage on I/O pins or RSTb	V_{IN}	V_{DD} > 3.3 V	GND-0.3	5.8	V
		V_{DD} < 3.3 V	GND-0.3	V_{DD}+2.5	V
Total Current Sunk into Supply Pin	I_{VDD}		—	200	mA
Total Current Sourced out of Ground Pin	I_{GND}		200	—	mA
Current Sourced or Sunk by any I/O Pin or RSTb	I_{IO}		-100	100	mA
Operating Junction Temperature	T_J	T_A = -40 °C to 85 °C	–40	105	°C
		T_A = -40 °C to 125 °C (I-grade or A-grade parts only)	-40	130	°C

Note:
1. Exposure to maximum rating conditions for extended periods may affect device reliability.

4.4 Typical Performance Curves

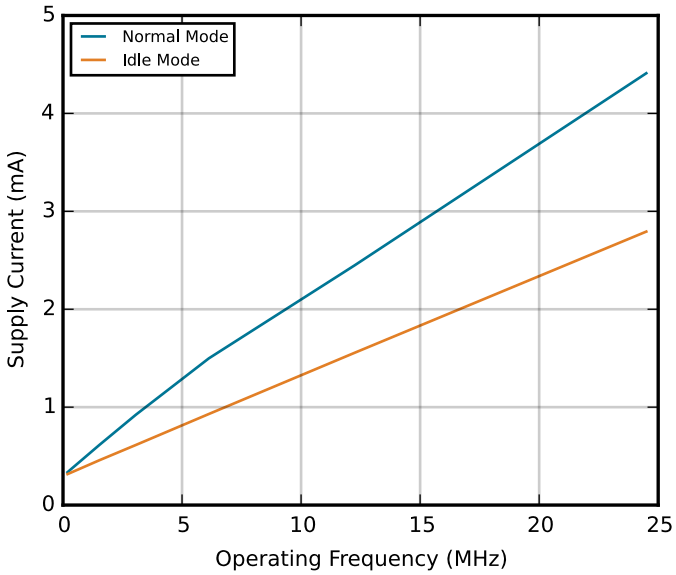

Figure 4.1. Typical Operating Supply Current using HFOSC0

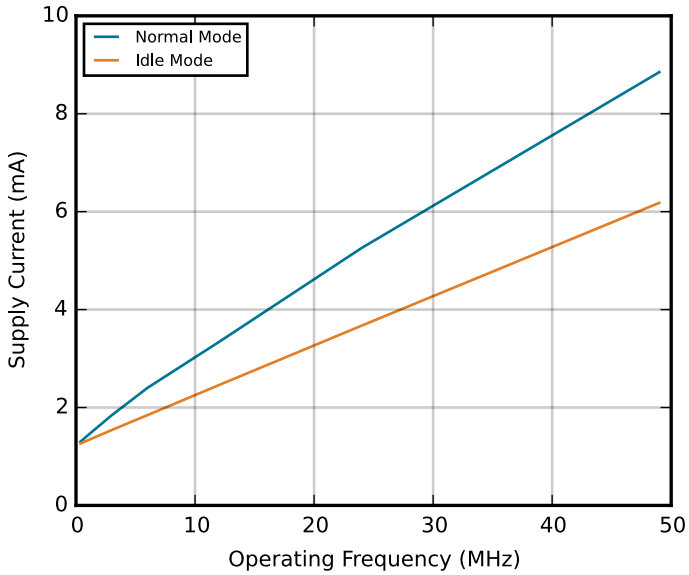

Figure 4.2. Typical Operating Supply Current using HFOSC1

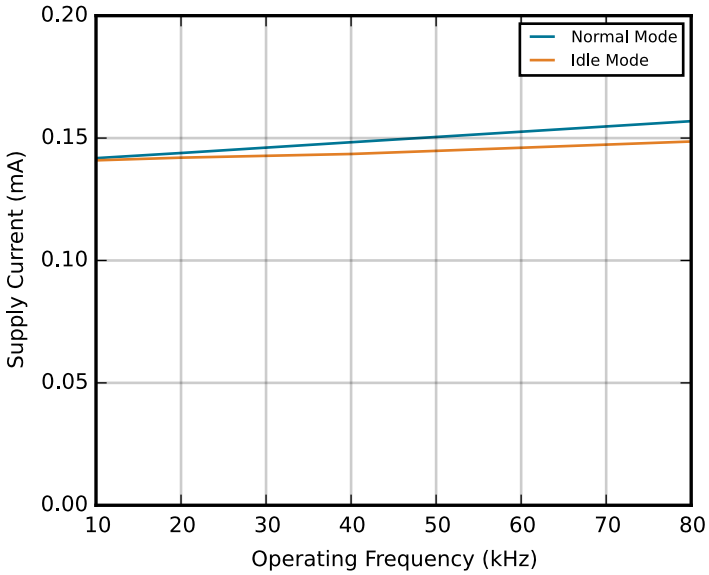

Figure 4.3. Typical Operating Supply Current using LFOSC

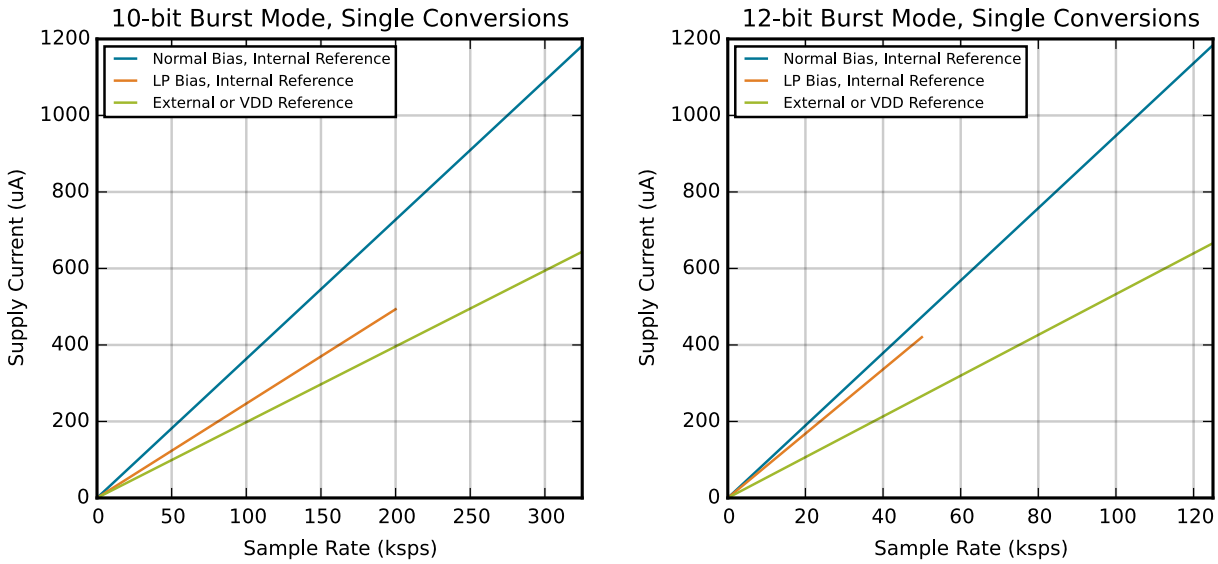

Figure 4.4. Typical ADC0 and Internal Reference Supply Current in Burst Mode

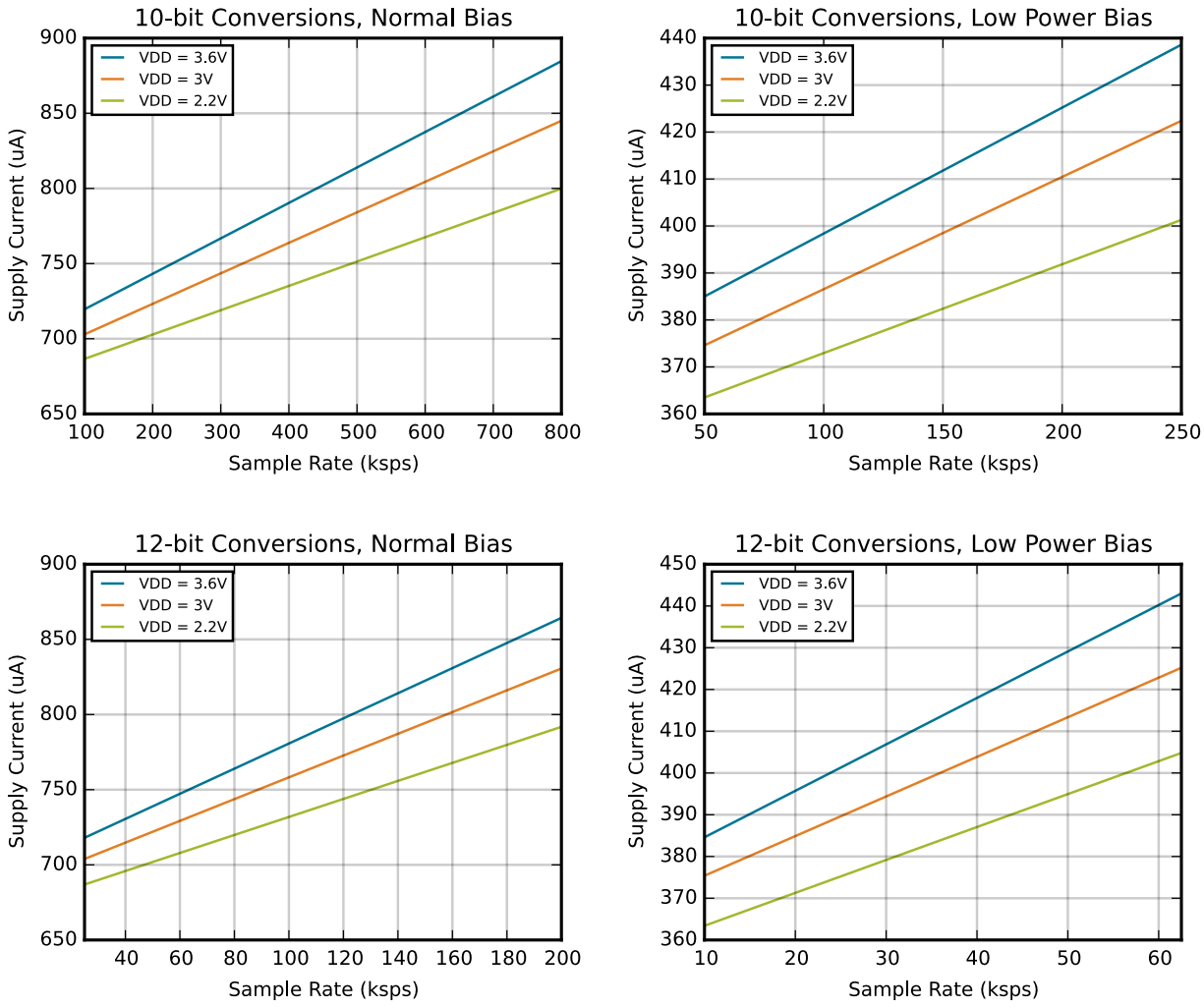

Figure 4.5. Typical ADC0 Supply Current in Normal (always-on) Mode

5.2 Debug

The diagram below shows a typical connection diagram for the debug connections pins. The pin sharing resistors are only required if the functionality on the C2D (a GPIO pin) and the C2CK (RSTb) is routed to external circuitry. For example, if the RSTb pin is connected to an external switch with debouncing filter or if the GPIO sharing with the C2D pin is connected to an external circuit, the pin sharing resistors and connections to the debug adapter must be placed on the hardware. Otherwise, these components and connections can be omitted.

For more information on debug connections, see the example schematics and information available in AN127: "Pin Sharing Techniques for the C2 Interface." Application notes can be found on the Silicon Labs website (http://www.silabs.com/8bit-appnotes) or in Simplicity Studio.

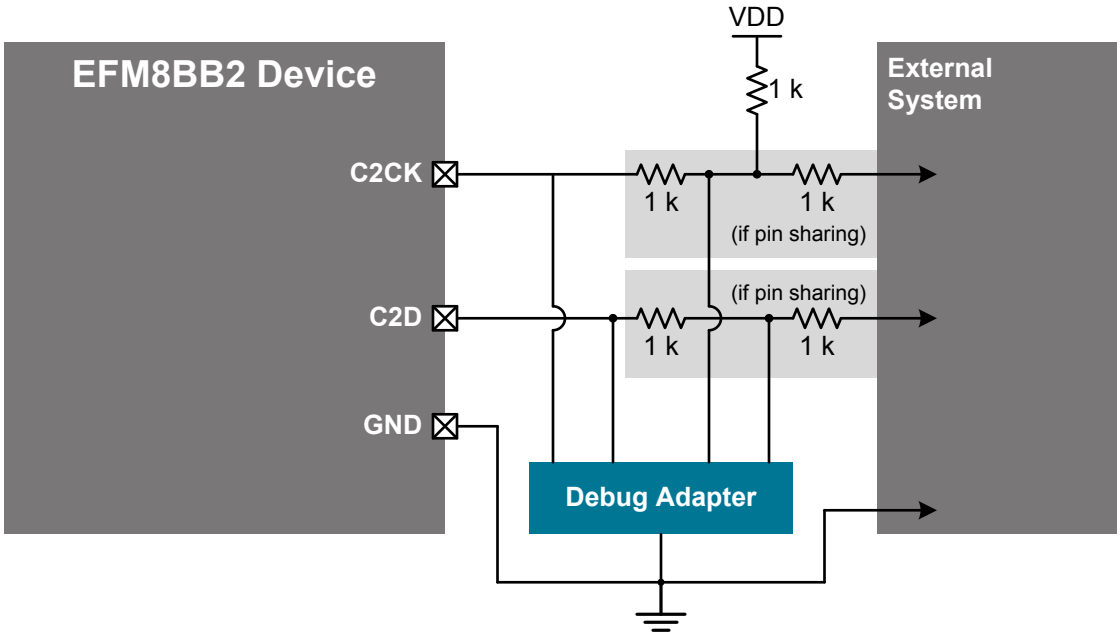

Figure 5.3. Debug Connection Diagram

5.3 Other Connections

Other components or connections may be required to meet the system-level requirements. Application note, "AN203: 8-bit MCU Printed Circuit Board Design Notes", contains detailed information on these connections. Application Notes can be accessed on the Silicon Labs website (www.silabs.com/8bit-appnotes).

6.3 EFM8BB2x-QFN20 Pin Definitions

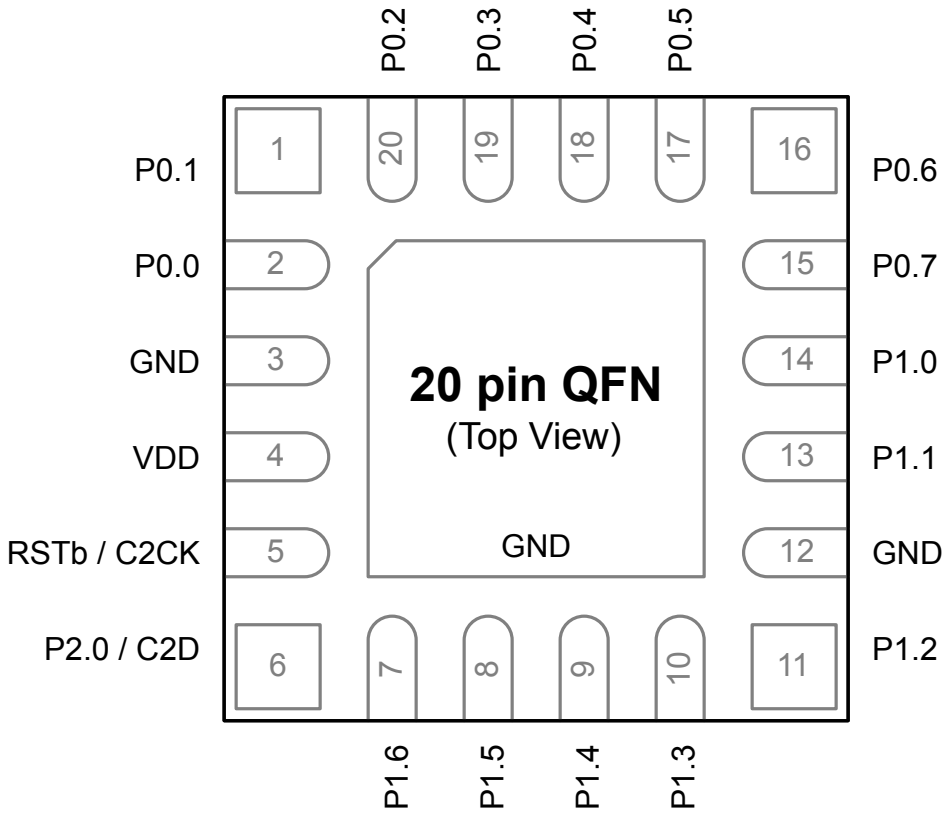

Figure 6.3. EFM8BB2x-QFN20 Pinout

Table 6.3. Pin Definitions for EFM8BB2x-QFN20

Pin Number	Pin Name	Description	Crossbar Capability	Additional Digital Functions	Analog Functions
1	P0.1	Multifunction I/O	Yes	P0MAT.1 INT0.1 INT1.1	ADC0.1 CMP0P.1 CMP0N.1 AGND
2	P0.0	Multifunction I/O	Yes	P0MAT.0 INT0.0 INT1.0	ADC0.0 CMP0P.0 CMP0N.0 VREF

Pin Number	Pin Name	Description	Crossbar Capability	Additional Digital Functions	Analog Functions
3	GND	Ground			
4	VDD	Supply Power Input			
5	RSTb / C2CK	Active-low Reset / C2 Debug Clock			
6	P2.0 / C2D	Multifunction I/O / C2 Debug Data	Yes		
7	P1.6	Multifunction I/O	Yes	P1MAT.6	ADC0.14 CMP1P.6 CMP1N.6
8	P1.5	Multifunction I/O	Yes	P1MAT.5	ADC0.13 CMP1P.5 CMP1N.5
9	P1.4	Multifunction I/O	Yes	P1MAT.4	ADC0.12 CMP1P.4 CMP1N.4
10	P1.3	Multifunction I/O	Yes	P1MAT.3 I2C0_SCL	ADC0.11 CMP1P.3 CMP1N.3
11	P1.2	Multifunction I/O	Yes	P1MAT.2 I2C0_SDA	ADC0.10 CMP1P.2 CMP1N.2
12	GND	Ground			
13	P1.1	Multifunction I/O	Yes	P1MAT.1	ADC0.9 CMP1P.1 CMP1N.1 CMP0P.10 CMP0N.10
14	P1.0	Multifunction I/O	Yes	P1MAT.0	ADC0.8 CMP1P.0 CMP1N.0 CMP0P.9 CMP0N.9
15	P0.7	Multifunction I/O	Yes	P0MAT.7 INT0.7 INT1.7	ADC0.7 CMP0P.7 CMP0N.7

7.2 QFN28 PCB Land Pattern

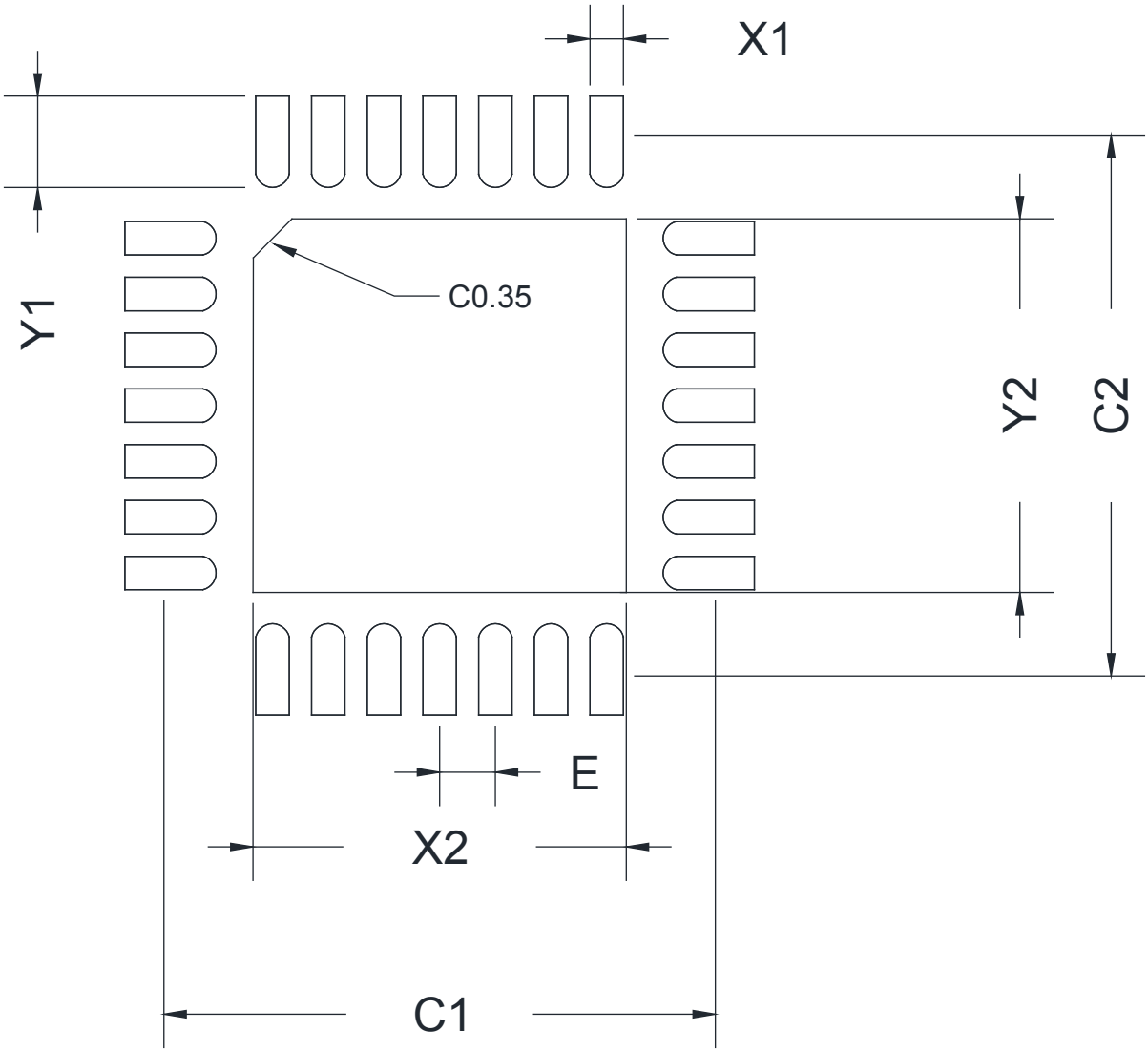

Figure 7.2. QFN28 PCB Land Pattern Drawing

Table 7.2. QFN28 PCB Land Pattern Dimensions

Dimension	Min	Max
C1	4.80	
C2	4.80	
E	0.50	
X1	0.30	
X2	3.35	
Y1	0.95	

Dimension	Min	Typ	Max
aaa		0.20	
bbb		0.18	
ccc		0.10	
ddd		0.10	

Note:

1. All dimensions shown are in millimeters (mm) unless otherwise noted.
2. Dimensioning and Tolerancing per ANSI Y14.5M-1994.
3. This drawing conforms to JEDEC outline MO-137, variation AE.
4. Recommended card reflow profile is per the JEDEC/IPC J-STD-020 specification for Small Body Components.

9.2 QFN20 PCB Land Pattern

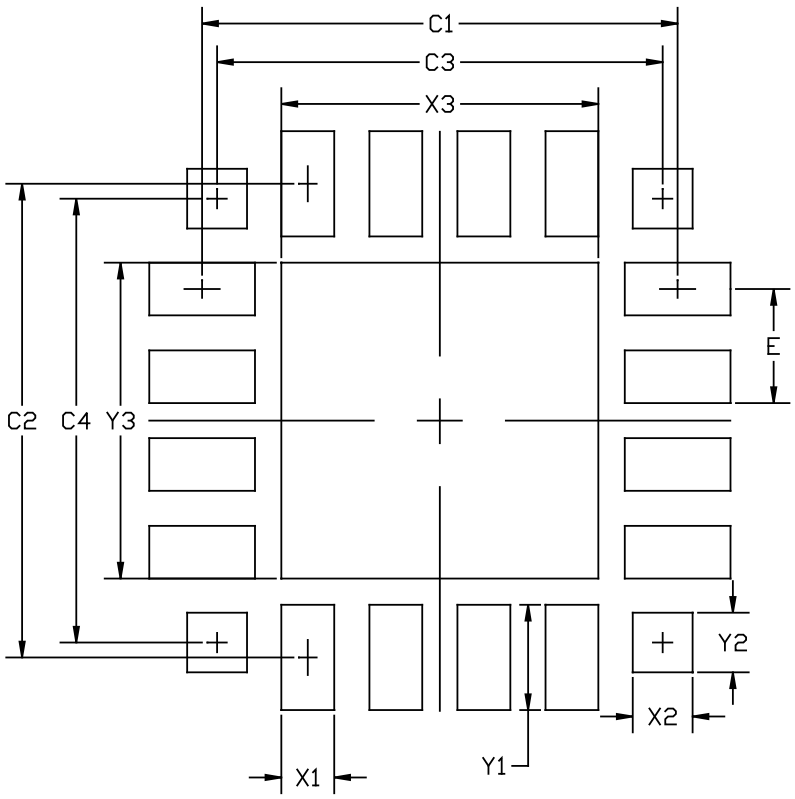

Figure 9.2. QFN20 PCB Land Pattern Drawing

Table 9.2. QFN20 PCB Land Pattern Dimensions

Dimension	Min	Max
C1	3.10	
C2	3.10	
C3	2.50	
C4	2.50	
E	0.50	
X1	0.30	
X2	0.25	0.35
X3	1.80	
Y1	0.90	
Y2	0.25	0.35
Y3	1.80	

10. Revision History

10.1 Revision 1.31

November 7, 2016

Updated typical and maximum specifications in 4.1.2 Power Consumption.

Added 4.1.11 1.8 V Internal LDO Voltage Regulator.

10.2 Revision 1.3

August 11, 2016

Added A-grade parts.

Added Thermal Resistance (Junction to Case) for QFN20 packages to 4.2 Thermal Conditions.

Added a note to Table 4.2 Power Consumption on page 13 providing more information about the Comparator Reference specification.

Added a note linking to the Typical VOH and VOL Performance graphs in 4.1.14 Port I/O.

Specified the sizes of the SMBus and I2CSLAVE transmit and receive FIFOs.

Added a note to 3.1 Introduction referencing the Reference Manual.

10.3 Revision 1.2

February 10, 2016

Updated Figure 5.3 Debug Connection Diagram on page 30 to move the pull-up resistor on C2D / RSTb to after the series resistor instead of before.

Added a reference to *AN945: EFM8 Factory Bootloader User Guide* in 3.10 Bootloader.

Added I-grade parts.

Adjusted and added maximum specifications in 4.1.2 Power Consumption for G-grade devices and added a note on which high frequency oscillator is used for the specification.

Adjusted the Total Current Sunk into Supply Pin and Total Current Sourced out of Ground Pin specifications in 4.3 Absolute Maximum Ratings.

10.4 Revision 1.1

December 16, 2015

Updated 3.2 Power to properly reflect that a comparator falling edge wakes the device from Suspend and Snooze.

Added Note 2 to Table 4.1 Recommended Operating Conditions on page 12.

Added 5.2 Debug.

10.5 Revision 1.0

Updated any TBD numbers in and adjusted various specifications.

Updated VOH and VOL graphs in Figure 4.6 Typical V_{OH} Curves on page 28 and Figure 4.7 Typical V_{OL} Curves on page 28 and updated the VOH and VOL specifications in Table 4.14 Port I/O on page 23.

Added more information to 3.10 Bootloader.

Updated part numbers to Revision C.